

Application/Control No.	Applicant(s)/Patent under Reexamination
10/806,338	OHASHI ET AL.
Examiner	Art Unit
David E. Martinez	2181

	SEARCHED					
Class	Subclass	Date	Examiner			
			:			
L.,						

INT	INTERFERENCE SEARCHED				
Class	Subclass	Date	Examiner		
		<u> </u>			

SEARCH NOT (INCLUDING SEARCH)
	DATE	EXMR
East see attached	7/10/2006	DM
Inventor search eDan / Palm	7/10/2006	DM
710/36-38.ccls. 714/1-4.ccls. with keywords and text search	7/10/2006	DM
Databases: US Patents, US PGPUBS, USOCR, EPO, JPO, Derwent, IBM_TDB.	7/10/2006	DM
		,